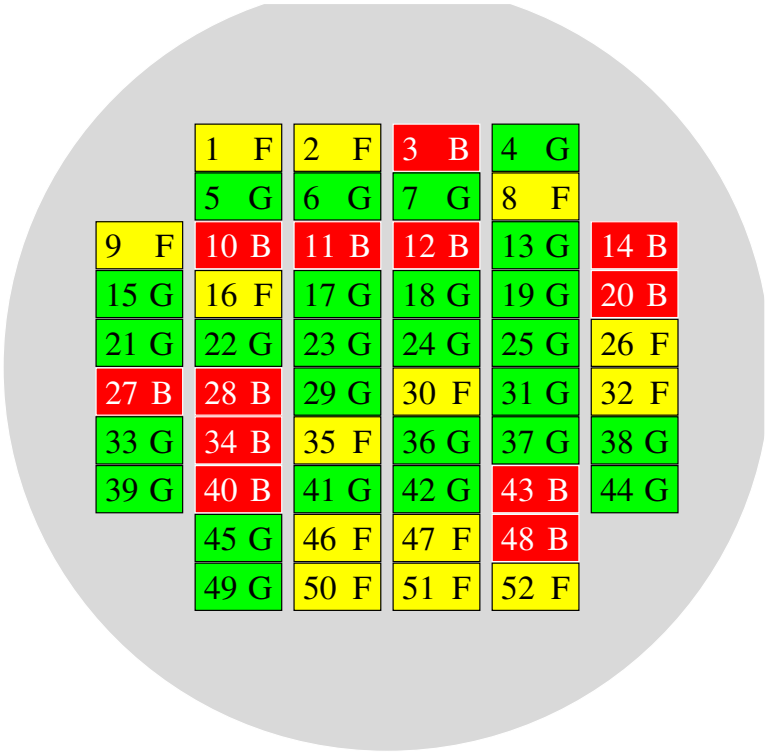
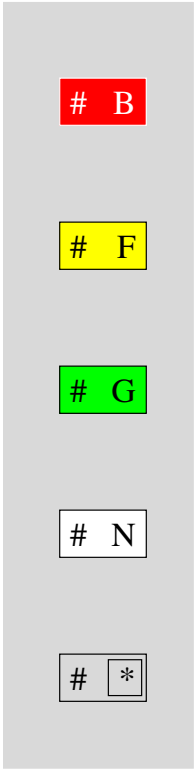
Die quality map for wafer 109 s/n: 21316-07-17

Date: 03/01/99





Bad die

Fair die

Good die

No info

Manually tagged